

<b>Notice of References Cited</b>	Application/Control No. 10/004,805	Applicant(s)/Patent Under Reexamination SHIMIZU ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,568,149	02-1986	Sugata et al.	349/111
	B	US-6,507,385	01-2003	Nishiyama et al.	349/156
	C	US-4,763,995	08-1988	Katagiri et al.	349/156
	D	US-6,004,423	12-1999	Ruedin et al.	156/292
	E	US-6,108,068	08-2000	Yano et al.	349/155
	F	US-6,414,739	07-2002	Suzuki, Seiji	349/155
	G	US-2002/0003519	01-2002	Kim, Yong Wan	345/87
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 3-54523	03-1991	Japan	Nomoto et al	
	O	JP 59-139018	08-1984	Japan	Miyajima et al	
	P	JP 3-223728	09-1988	Japan	Tanaka et al	
	Q	JP 3-287127	12-1991	Japan	Tatemichi	
	R	JP 2001-142076	05-2001	Japan	Manabe et al	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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